



FDP20N50F / FDPF20N50FT

N-Channel UniFET™ FRFET® MOSFET

500 V, 20 A, 260 mΩ

Features

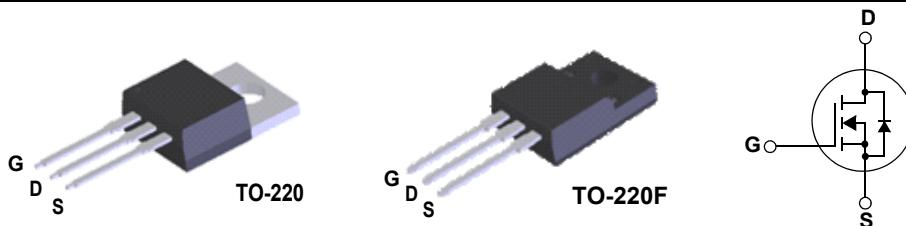
- $R_{DS(on)} = 210 \text{ m}\Omega$ (Typ.) @ $V_{GS} = 10 \text{ V}$, $I_D = 10 \text{ A}$
- Low Gate Charge (Typ. 50 nC)
- Low C_{rss} (Typ. 27 pF)
- 100% Avalanche Aested
- Improve dv/dt Capability
- RoHS Compliant

Applications

- LCD/LED/PDP TV
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply

Description

UniFET™ MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. The body diode's reverse recovery performance of UniFET FRFET® MOSFET has been enhanced by lifetime control. Its t_{rr} is less than 100nsec and the reverse dv/dt immunity is 15V/ns while normal planar MOSFETs have over 200nsec and 4.5V/nsec respectively. Therefore, it can remove additional component and improve system reliability in certain applications in which the performance of MOSFET's body diode is significant. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter		FDP20N50F	FDPF20N50FT	Unit
V_{DSS}	Drain to Source Voltage		500		V
V_{GSS}	Gate to Source Voltage			± 30	V
I_D	Drain Current	- Continuous ($T_C = 25^\circ\text{C}$)	20	20*	A
		- Continuous ($T_C = 100^\circ\text{C}$)	12.9	12.9*	
I_{DM}	Drain Current	- Pulsed (Note 1)	80	80*	A
E_{AS}	Single Pulsed Avalanche Energy (Note 2)		1110		mJ
I_{AR}	Avalanche Current (Note 1)		20		A
E_{AR}	Repetitive Avalanche Energy (Note 1)		25		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		20		V/ns
P_D	Power Dissipation	($T_C = 25^\circ\text{C}$)	250	38.5	W
		- Derate above 25°C	2.0	0.3	$W/\text{^\circ C}$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to $+150$		$^\circ\text{C}$
T_L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300		$^\circ\text{C}$

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FDP20N50F	FDPF20N50FT	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.5	3.3	$^\circ\text{C/W}$
$R_{\theta CS}$	Thermal Resistance, Case to Sink, Typ.	0.5	-	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	62.5	

Package Marking and Ordering Information $T_C = 25^\circ\text{C}$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP20N50F	FDP20N50F	TO-220	-	-	50
FDPF20N50FT	FDPF20N50FT	TO-220F	-	-	50

Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
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Off Characteristics

BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}, T_J = 25^\circ\text{C}$	500	-	-	V
$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, Referenced to 25°C	-	0.7	-	$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 500\text{V}, V_{GS} = 0\text{V}$	-	-	10	μA
		$V_{DS} = 400\text{V}, T_C = 125^\circ\text{C}$	-	-	100	
I_{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30\text{V}, V_{DS} = 0\text{V}$	-	-	± 100	nA

On Characteristics

$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	3.0	-	5.0	V
$R_{DS(\text{on})}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 10\text{A}$	-	0.22	0.26	Ω
g_{FS}	Forward Transconductance	$V_{DS} = 20\text{V}, I_D = 10\text{A}$	-	25	-	S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	2550	3390	pF
C_{oss}	Output Capacitance		-	350	465	pF
C_{rss}	Reverse Transfer Capacitance		-	27	40	pF
$Q_{g(\text{tot})}$	Total Gate Charge at 10V	$V_{DS} = 400\text{V}, I_D = 20\text{A}$ $V_{GS} = 10\text{V}$	-	50	65	nC
Q_{gs}	Gate to Source Gate Charge		-	14	-	nC
Q_{gd}	Gate to Drain "Miller" Charge		(Note 4)	-	20	nC

Switching Characteristics

$t_{d(\text{on})}$	Turn-On Delay Time	$V_{DD} = 250\text{V}, I_D = 20\text{A}$ $R_G = 25\Omega$	-	45	100	ns
t_r	Turn-On Rise Time		-	120	250	ns
$t_{d(\text{off})}$	Turn-Off Delay Time		-	100	210	ns
t_f	Turn-Off Fall Time		(Note 4)	-	60	130

Drain-Source Diode Characteristics

I_S	Maximum Continuous Drain to Source Diode Forward Current	-	-	20	A	
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	80	A	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 20\text{A}$	-	-	1.5	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_{SD} = 20\text{A}$	-	154	-	ns
Q_{rr}	Reverse Recovery Charge	$dI_F/dt = 100\text{A}/\mu\text{s}$	-	0.5	-	μC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. $L = 5\text{mH}, I_{AS} = 20\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 20\text{A}, di/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq \text{BV}_{\text{DSS}}$, Starting $T_J = 25^\circ\text{C}$
4. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

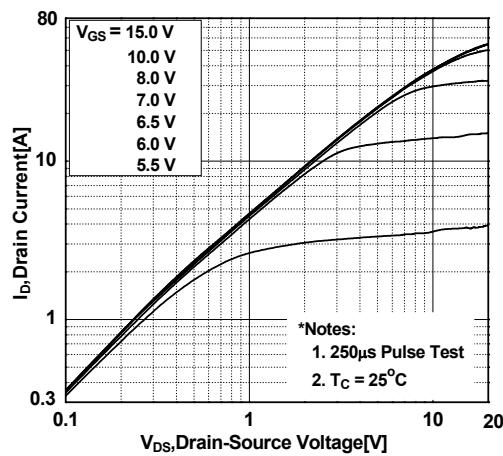


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

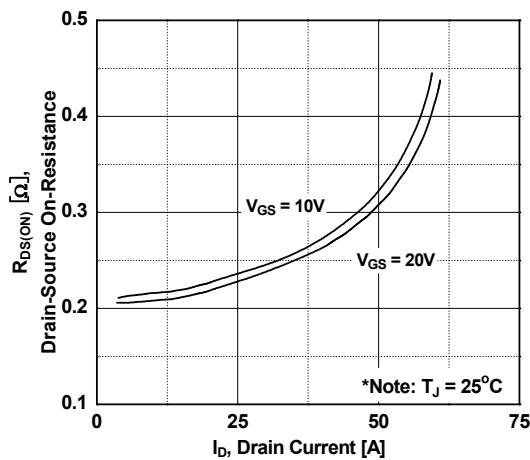


Figure 5. Capacitance Characteristics

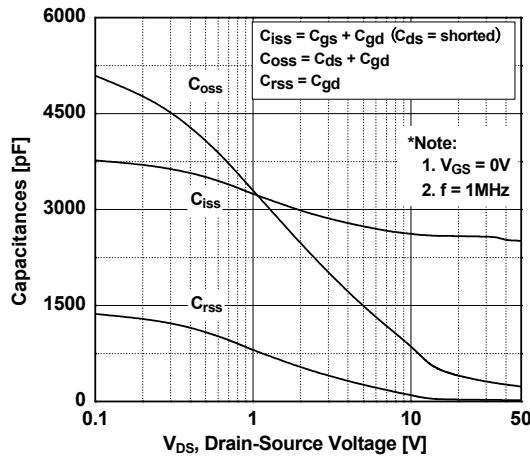


Figure 2. Transfer Characteristics

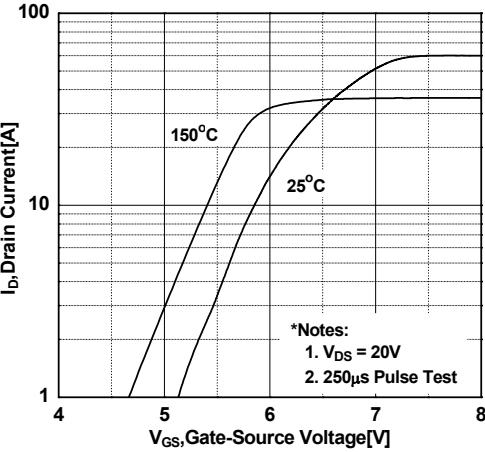


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

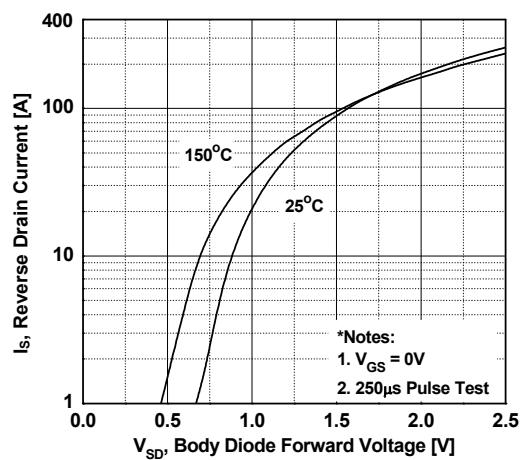


Figure 6. Gate Charge Characteristics

